



501.42867X00

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): I. OCHIAI, et al

Serial No.: 10/601,531

Filed: June 24, 2003

For: ELECTRON MICROSCOPE INCLUDING APPARATUS FOR X-RAY ANALYSIS AND METHOD OF ANALYZING SPECIMENS USING SAME

Group: 2881

Examiner: D. Vanore

**AMENDMENT**

Mail Stop Non-Fee Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

February 11, 2004

Sir:

In response to the Office Action November 12, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application, as listed below and as set forth on the following pages:

Amendment of the Claims; and

Remarks are included following the amendments.